

IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (currently amended)      An x-ray examination apparatus comprising an x-ray source and an x-ray detector,

~~-----the x-ray detector including having~~

~~-----a photoconductor to derive electric charges from incident x-radiation and~~

~~-----read-out elements which that derive electrical pixel-signals from the electric charges~~

~~from of the photoconductor and~~

~~-----an output circuit to output the electrical pixel-signal from the read-out elements,~~

wherein

~~-----a central group of the read-out elements is located in a central region of the x-ray~~

detector and

~~-----a peripheral group of the read-out elements is located in a peripheral region which that~~

surrounds the central region,

~~-----the x-ray examination apparatus being provided with further having~~

~~-----a selection system to select the central group of read-out elements so as to supply pixel-~~

signals from the central group of read-elements to the output circuit.

2. (currently amended)      ~~An The~~ x-ray examination apparatus as claimed in Claim ~~of~~  
~~claim~~ 1, wherein the selection system includes an x-ray shielding member ~~which that~~ shields the  
peripheral region of the photoconductor from incident x-radiation.

3. (currently amended) ~~An~~The x-ray examination apparatus ~~as claimed in Claim of~~  
~~claim 1, and further~~ comprising a collimator between the x-ray detector~~source~~ and the x-ray detector,  
wherein the collimator ~~comprises~~has an x-ray absorbing member ~~which~~that is spatially registered  
with the peripheral region of the photoconductor.

4. (currently amended). ~~An~~The x-ray examination apparatus ~~as claimed in Claim of~~  
~~claim 1, wherein and wherein~~ the selection system ~~includes~~has an encompassing electrode ~~which~~  
~~surrounds at least substantially surrounding~~ the central region and ~~which is~~ electrically connected to  
the read-out elements of the peripheral group.

5. (currently amended) ~~An~~The x-ray examination apparatus ~~as claimed in Claim of~~  
~~claim 1, wherein~~ collecting electrodes of read-out elements of the peripheral group are smaller sized  
than collecting electrodes of the read-out elements the central group.

6. (currently amended) ~~An~~The x-ray examination apparatus ~~as claimed in Claim of~~  
~~claim 1, wherein~~ the selection system electrically isolates the peripheral group of read-out elements  
from the output circuit.

7. (currently amended) ~~An~~The x-ray examination apparatus ~~as claimed in Claim of~~  
~~claim 1, wherein~~ the photoconductor is a continuous semiconductor layer or the photoconductor  
includes a plurality of crystalline semiconductor elements.

8. (currently amended) ~~As the~~ x-ray examination apparatus ~~as claimed in Claim of~~  
claim 7, wherein the semiconductor layer or the semiconductor elements contain a photoconducting  
material from the group of Cadmium Zinc Telluride, Mercury Iodide or Lead Oxide.